PLUS Search Results for S/N 09887759, Searched July 29, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system, which produces a list of patents that are most closely related linguistically to the application searched. The staff of the Scientific and Technical Information Center, SIRA prepared this search.

	Contor, Bird's propared
6721730	6477525
5590324	5899986
6092062	6029163
5548755	6003040
5797136	6189012
6529896	5551031
5905982	5557791
5724570	5819255
5822750	6265636
5761653	6313375
5546576	6313376
5551029	6388169
5940819	5412804
5873075	5864842
6345267	5895465
5367675	6108651
5774692	6243709
6032144	6684203
6061676	6748392
6061676	5819268
5745746	5761493
5778355	5826077
6438741	5829006
6131078	5850544
5864840	5752016
6032143	5765159
5548758	5799309
5548754	5819282
RE37965	5893108
6014664	6442566
6317700	6708186
6026390	6735598
5546526	5291583
5469568	5295256
5542073	5197005

5732258
5778354
5884299
6339769
6438538
5600829
5615361
6138111
5574900
5787411
5999924
6009265
6125360
6192357
6339768

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

i i i i i i i i i i i i i i i i i i i	ions/Services Standards Conferences Careers/Jobs
IEEE X	Welcome United States Patent and Trademark Office
Help FAQ Terms IEEE Review	Peer Quick Links ▼ Sea
Welcome to IEEE Xplore*	
O- Home O- What Can I Access?	Your search matched 7 of 1058483 documents. A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order.
O- Log-out	Refine This Search:
Tables of Contents	You may refine your search by editing the current search expression or enterinew one in the text box.
O- Journals & Magazines	Search
O- Conference Proceedings	☐ Check to search within this result set
O- Standards	Results Key:
Search	JNL = Journal or Magazine CNF = Conference STD = Standard
O- By Author O- Basic O- Advanced	1 Local and global constraints in database integration Gamal-Eldin, M.S.; Thomas, G.; Elmasri, R.; System Sciences, 1989. Vol.II: Software Track, Proceedings of the Twenty-Se
Member Services	Annual Hawaii International Conference on , Volume: 2 , 3-6 Jan. 1989 Pages:604 - 611 vol.2
O- Join IEEE O- Establish IEEE Web Account	[Abstract] [PDF Full-Text (616 KB)] IEEE CNF
O- Access the IEEE Member Digital Library	2 Fixed points vs. infinite generation Niwinski, D.; Logic in Computer Science, 1988. LICS '88., Proceedings of the Third Annual Symposium on , 5-8 July 1988
O- Access the IEEE Enterprise	Pages:402 - 409 [Abstract] [PDF Full-Text (424 KB)] IEEE CNF
File Cabinet	
Print Format	3 Fuzzy-operators weight refinements Manic, M.; Reliability and Maintainability Symposium, 1999. Proceedings. Annual, 18-2: 1999 Pages: 245 - 251
	[Abstract] [PDF Full-Text (948 KB)] IEEE CNF
	4 A fuzzy logic approach to detector scoring Keller, J.; Moore, J.; Gader, P.;

Fuzzy Information Processing Society - NAFIPS, 1998 Conference of the North American, 20-21 Aug. 1998

Pages:339 - 344

[Abstract] [PDF Full-Text (496 KB)] IEEE CNF



Xiaodong Wang; Anrong Dang;

Geoscience and Remote Sensing Symposium, 2000. Proceedings. IGARSS 201

IEEE 2000 International, Volume: 5, 24-28 July 2000

Pages:2131 - 2133 vol.5

[Abstract] [PDF Full-Text (192 KB)] IEEE CNF

6 Fuzzy types: softening structures

Marin, N.; Vila, M.A.; Pons, O.;

Fuzzy Systems, 2000. FUZZ IEEE 2000. The Ninth IEEE International Confere

on , Volume: 2 , 7-10 May 2000

Pages:774 - 779 vol.2

[Abstract] [PDF Full-Text (388 KB)] IEEE CNF

7 Performance evaluation of fuzzy neural network with various aggregation operators

Patil, P.M.; Kulkarni, U.V.; Sontakke, T.R.; Neural Information Processing, 2002. ICONIP '02. Proceedings of the 9th International Conference on , Volume: 4 , 18-22 Nov. 2002 Pages:1744 - 1748 vol.4

[Abstract] [PDF Full-Text (363 KB)] IEEE CNF

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved